

Software Requirements Specifications (SRS) STEM Moiré GPA

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Contents

| | | |
|----------|--|------------|
| 1 | Revision History | ii |
| 2 | Reference Material | iii |
| 2.1 | Table of Units | iii |
| 2.2 | Table of Symbols | iii |
| 2.3 | Abbreviations and Acronyms | v |
| 3 | Introduction | 1 |
| 3.1 | Purpose of Document | 1 |
| 3.2 | Scope of Requirements | 1 |
| 3.3 | Characteristics of Intended Reader | 1 |
| 3.4 | Organization of Document | 1 |
| 4 | General System Description | 1 |
| 4.1 | System Context | 1 |
| 4.2 | User Characteristics | 2 |
| 4.3 | System Constraints | 2 |
| 5 | Specific System Description | 2 |
| 5.1 | Problem Description | 2 |
| 5.1.1 | Terminology and Definitions | 3 |
| 5.1.2 | Physical System Description | 5 |
| 5.1.3 | Goal Statements | 5 |
| 5.2 | Solution Characteristics Specification | 5 |
| 5.2.1 | Assumptions | 5 |
| 5.2.2 | Theoretical Models | 6 |
| 5.2.3 | General Definitions | 8 |
| 5.2.4 | Data Definitions | 9 |
| 5.2.5 | Instance Models | 11 |
| 5.2.6 | Data Constraints | 14 |
| 5.2.7 | Properties of a Correct Solution | 14 |
| 6 | Requirements | 14 |
| 6.1 | Functional Requirements | 14 |
| 6.2 | Nonfunctional Requirements | 15 |
| 7 | Likely Changes (or Possible Changes) | 16 |
| 8 | Traceability Matrices and Graphs | 16 |
| 9 | Appendix | 21 |
| 9.1 | Symbolic Parameters | 21 |

1 Revision History

Table 1: **Revision History**

| Date | Version | Notes |
|-----------|---------|-------------|
| 1/10/2017 | 1.0 | First Draft |

2 Reference Material

2.1 Table of Units

Throughout this document SI ([Système Internationale d'Unités](#)) is employed as the unit system. In addition to the basic units, several derived units are used as described below. For each unit, the symbol is given followed by a description of the unit and the SI name.

| Symbol | Base quantity | Name SI |
|-----------------|------------------|-------------|
| m | length | metre |
| m ⁻¹ | reciprocal meter | wave number |

2.2 Table of Symbols

The table that follows summarizes the symbols used in this document along with their units if applicable.

| Symbol | Unit | Description |
|------------------------------|------------------|---|
| \mathcal{B} | | 2D orthonormal base |
| \mathcal{C} | | Ceiling function |
| δ | | Dirac delta function |
| $\Delta \vec{g}_j^{M_{exp}}$ | nm ⁻¹ | Variation of the j^{th} Moiré wave vector of SMH_{exp} |
| $\Delta \vec{g}_j^{C_{exp}}$ | nm ⁻¹ | Variation of the j^{th} crystalline wave vector of SMH_{exp} |
| ε | | Strain tensor |
| ε_{xx} | | Uniaxial strain component along \vec{u}_x |
| ε_{yy} | | Uniaxial strain component along \vec{u}_y |
| ε_{xy} | | Shear strain component in base \mathcal{B} |
| \mathcal{FT} | | Fourier transform |
| Γ | | Spatial frequency range |
| \vec{g}_j | nm ⁻¹ | j^{th} wave vector |
| g_{j_x} | nm ⁻¹ | Component of the j^{th} wave vector along \vec{u}_x |
| g_{j_y} | nm ⁻¹ | Component of the j^{th} wave vector along \vec{u}_y |
| \vec{g}_j^C | nm ⁻¹ | j^{th} crystalline wave vector |
| $\vec{g}_j^{C_{ref}}$ | nm ⁻¹ | j^{th} crystalline wave vector of $I_{C_{ref}}$ |
| $\vec{g}_j^{C_{exp}}$ | nm ⁻¹ | j^{th} crystalline wave vector of SMH_{exp} |
| $\vec{g}_j^{C_{exp}}$ | nm ⁻¹ | j^{th} crystalline wave vector of SMH_{exp} at its unstrained state |
| $\vec{g}_j^{M_{exp}}$ | nm ⁻¹ | j^{th} Moiré wave vector of SMH_{exp} |
| $\vec{g}_j^{M_{exp}}$ | nm ⁻¹ | j^{th} Moiré wave vector of SMH_{exp} at its unstrained state |

| | | |
|---------------------------------|------------------|---|
| i | | Imaginary unit |
| I | | Intensity (or number of counts) |
| \mathbb{I} | | Sub-set of \mathbb{R} representing the position of the pixels in an image |
| $I_{C_{ref}}$ | | 2D array representing the reference crystal structure |
| $I_{SMF_{exp}}$ | | 2D array representing the experimental SMH |
| $I_{SMF_{sim}}$ | | 2D array representing the simulated SMH |
| $I_{\varepsilon_{xx}}$ | | 2D array representing the uniaxial strain component along \vec{u}_x |
| $I_{\varepsilon_{yy}}$ | | 2D array representing the uniaxial strain component along \vec{u}_y |
| $I_{\varepsilon_{xy}}$ | | 2D array representing the shear strain component in base \mathcal{B} |
| M_j | | Mask function in Fourier space including the j^{th} wave vector |
| \mathbb{N} | | Set of natural numbers |
| ∇ | | Gradient operator |
| ∇u | | Displacement gradient tensor |
| $\vec{\nu}$ | nm^{-1} | Vector position in Fourier space |
| ω | | Rotation tensor |
| ω_{xy} | rad | Rotation element of the rotation tensor |
| p | nm | Pixel size |
| $P_{\vec{X}}$ | rad | 2D array representing $2\pi \vec{X} \cdot \vec{r}$ |
| $\overrightarrow{q_{n_j, m_j}}$ | | Sampling vector $\vec{q} \in Q$ of couple (n_j, m_j) |
| Q | | Set such that $Q = \{\forall(n, m) \in \mathbb{Z}^2, \vec{q} = n\vec{u}_x + m\vec{u}_y\}$ |
| \vec{r} | nm | Vector position |
| \mathbb{R} | | Set of real numbers |
| rot | | Curl operator |
| SMH_{exp} | | 2D array representing the experimental STEM Moiré Hologram |
| SMH_{sim} | | 2D array representing the simulated STEM Moiré Hologram |
| \vec{u}_x | | Unitary vector from base \mathcal{B} |
| \vec{u}_y | | Unitary vector from base \mathcal{B} |
| \wedge | | Cross product operator |
| \mathbb{Z} | | Set of integer numbers |

2.3 Abbreviations and Acronyms

| symbol | description |
|--------|---|
| A | Assumption |
| AU | Arbitrary Unit |
| DC | Data Constraint |
| DD | Data Definition |
| EM | Electron Micrograph |
| GD | General Definition |
| GPA | Geometrical Phase Analysis |
| GS | Goal Statement |
| IM | Instance Model |
| LC | Likely Change |
| PS | Physical System Description |
| NR | Non functional Requirement |
| R | Requirement |
| SMH | STEM Moiré Hologram |
| SRS | Software Requirements Specification |
| STEM | Scanning Transmission Electron Microscopy |
| T | Theoretical Model |

3 Introduction

3.1 Purpose of Document

The purpose of the document is to provide a detailed description of the functional and the non-functional requirements of the STEM Moiré GPA software. The theoretical models on which the requirements are based on are also described to provide the context of each instance model.

3.2 Scope of Requirements

The scope of requirements are limited to the realization of GS 1 which corresponds to transform a certain type of data to another one based on multiple user inputs.

3.3 Characteristics of Intended Reader

The intended reader is expected to have a minimum knowledge in mathematics at undergraduate level. Simplification of some physical concepts are proposed to make the document technically accessible. Nevertheless, a basic knowledge in Transmission Electron Microscopy, electron/matter interaction and elastic strain theory is recommended to get a deeper understanding of the document.

3.4 Organization of Document

The document follows the template of the SRS document proposed by [1, 2].

4 General System Description

This section identifies the interfaces between the system and its environment, describes the user characteristics and lists the system constraints.

4.1 System Context

STEM Moiré GPA is intended to transform specific data acquired microscope into physical information related to the sample analysed. The variety of samples is potentially huge therefore to cover the maximum of cases, multiple interactions with the user are required to process the data correctly. Responsibilities between the user and the STEM Moiré GPA are described as follows:

- User Responsibilities:
 - Provide the minimum information required by the STEM Moiré GPA software.
 - Use the software in the limits it is intended to.

- Be aware of the potential effects of user inputs on the quality of the final data.
 - Judge the correctness of the data.
 - Be particularly cautious on the use of the final data quantitatively. The quantitative aspect cannot be fully uncorrelated from the user inputs.
 - Use a pointing device, a keyboard and a display to interface with STEM Moiré GPA.
- STEM Moiré GPA Responsibilities:
 - Preserve the integrity of original data and not add any hidden processing steps on the final data such as, but not limited to, smoothing, blurring, averaging, de-noising and binning.
 - Inform user of wrong format or missing information regarding the inputs.
 - Inform the user of a potential insufficient quality of the final results which could lead to non reliable physical interpretations.

4.2 User Characteristics

The end user of STEM Moiré GPA should have a relative strong background in Physics, Mathematics and Electron Microscopy to get a reliable sense of the data processed. The multiple interactions between the user and STEM Moiré GPA have a significant impact on the final results which can lead to some physical misinterpretations.

4.3 System Constraints

STEM Moiré GPA is for the moment limited to the study of mono-crystalline material undergoing a relative small deformation with respect to its unstrained state. Another constraint is to be considered because of the electron microscopy community. Most of the files acquired on the microscope are in dm3 format, a non-standard format used by the detector manufacturer. Therefore, STEM Moiré GPA software needs to be able to read any dm3 files to be considered by the research community.

5 Specific System Description

5.1 Problem Description

STEM Moiré GPA project is a software capable of converting a STEM Moiré hologram into 2D relative strain maps. Terminologies, the context and a detailed description of the physical system is proposed below.

5.1.1 Terminology and Definitions

Regarding the complexity of the electron/matter interaction, some crude simplifications are proposed to describe the terminologies below. While sometimes not realistic, the simplifications should help in visualizing the context and the type of data the STEM Moiré GPA software is subjected to. Nevertheless, all the simplifications proposed are not affecting the definition of the concept used at the software level.

- **2D Cartesian coordinate system:** orthonormal coordinate system model by the orthonormal base $\mathcal{B} = (O, \vec{u}_x, \vec{u}_y)$ such that any vector \vec{r} can be expressed as the following:

$$\forall (x, y) \in \mathbb{R}^2, \vec{r} = x\vec{u}_x + y\vec{u}_y \quad (1)$$

- **Pixel:** smallest addressable element sampling a 2D continuum.
- **Electron Micrograph (EM):** 2D array collected in an electron microscope representing the number of electron crossing the sample (intensity) at each pixel location.
- **Scanning grid:** set representing the succession of the STEM probe positions when collecting the STEM EM. Equivalently the scanning grid represents the relative position of the pixel with respect to the sample when acquiring the EM. A simplified version of the STEM EM formation can be visualized in fig. 1. The positions of the STEM probe are located at the intersection of the black grid lines.

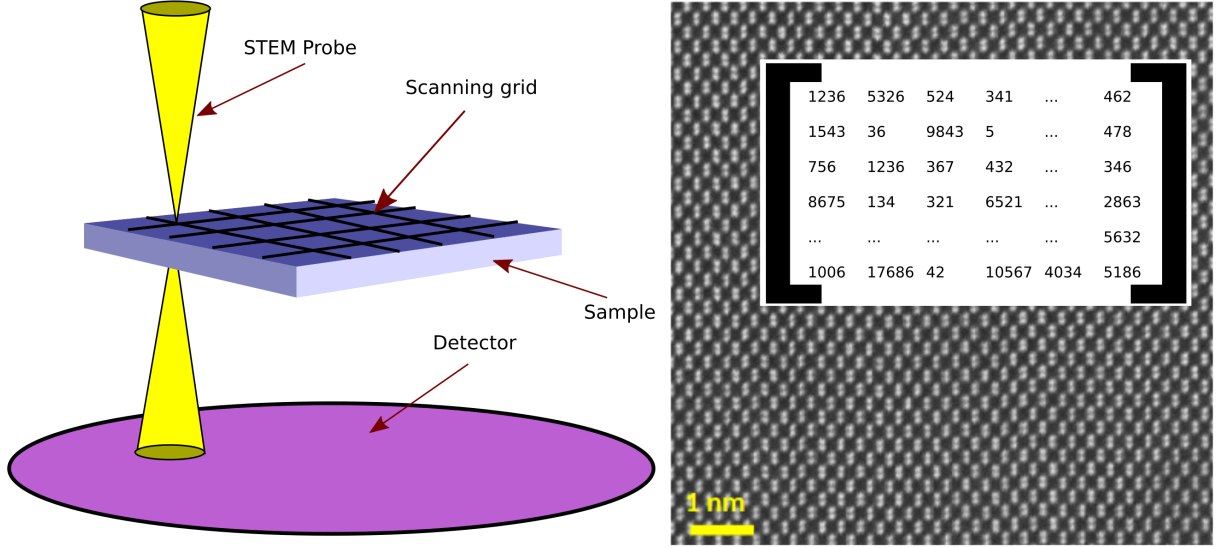


Figure 1: On the left hand side, a schematic of the STEM EM formation with the STEM probe scanning the sample at each intersection of the grid lines. The electrons crossing the sample are collected on the detector and counted during the acquisition time. On the right hand side is presented a STEM EM on a pure silicon sample revealing its atomic structure. In the inset is highlighted the type of data the STEM EM corresponds to which is a 2D array with the intensity collected on each element of the array.

- **Hologram:** Result from an interference between two or multiples waves.

Let consider two monochromatic plane waves ψ_1 and ψ_2 with their respective amplitude A_j , phase ϕ_j and wave vector \vec{k}_j in the 2D Cartesian system interfering with each other. The resulting hologram ψ_H represented by the intensity I_H can be modelled as follows with :

$$\forall (x, y) \in \mathbb{R}^2, \psi_H(\vec{r}) = \psi_1 + \psi_2 = A_1 e^{i(\vec{k}_1 \cdot \vec{r}) + i\phi_1} + A_2 e^{i(\vec{k}_2 \cdot \vec{r}) + i\phi_2} \quad (2)$$

$$\forall (x, y) \in \mathbb{R}^2, I_H(\vec{r}) = \psi_H \psi_H^* = A_1^2 + A_2^2 + A_1 A_2 (e^{i(\vec{k}_1 - \vec{k}_2) \cdot \vec{r} + i(\phi_1 - \phi_2)} + e^{i(\vec{k}_2 - \vec{k}_1) \cdot \vec{r} + i(\phi_2 - \phi_1)}) \quad (3)$$

The more waves are contributing to the hologram, the more complex eq. (3) will be. However, similar factors will appear with constants and cross product terms.

- **Moiré hologram:** Result from interference between two or multiple waves with similar but not equal wave numbers (or wave vectors in 2D).
- **Crystal lattice:** Periodic arrangement of atoms forming matter.
- **STEM Moiré hologram (SMH):** EM collected in STEM and resulting from the Moiré interference between the scanning grid and the crystal lattice.

- **Strain map:** 2D array mapping the evolution of one element of the 2D strain or rotation tensor.

5.1.2 Physical System Description

The physical system of STEM Moiré GPA, as shown in Figure ?, includes the following elements:

5.1.3 Goal Statements

Given the system description, the goal statement is:

GS 1 Extract and display the relative 2D strain field from a STEM Moiré hologram.

5.2 Solution Characteristics Specification

5.2.1 Assumptions

A 1 The microscope has a limit in resolution corresponding to the probe size and thus cannot resolve any spatial frequency higher than g_{lim} .

A 2 Since the STEM EM is discretized in pixels, the smallest feature detectable is composed of two pixels. Therefore, in reciprocal space, the maximum range of spatial frequency detectable is $\Gamma = [-\frac{1}{2p}, \frac{1}{2p}]^2$.

A 3 The probe size is smaller than the area covered by one pixel. Therefore, information gathered on one pixel is only provided by the area covered by the pixel (no blurring) and **A 1** is the only limiting factor regarding resolution.

A 4 The variation of the deformation field is small. Therefore,

$$\begin{aligned} \forall \vec{r} \in \mathbb{R}^2, \nabla(\Delta \vec{g}_j \cdot \vec{r}) &= (\Delta \vec{g}_j \cdot \nabla) \vec{r} + (\vec{r} \cdot \nabla) \Delta \vec{g}_j + \Delta \vec{g}_j \wedge \text{rot}(\vec{r}) + \vec{r} \wedge \text{rot}(\Delta \vec{g}_j) \\ \forall \vec{r} \in \mathbb{R}^2, \nabla(\Delta \vec{g}_j \cdot \vec{r}) &\approx \Delta \vec{g}_j \end{aligned}$$

A 5 The deformation magnitude is small. Therefore, $\frac{\|\Delta \vec{g}_j\|}{\|\vec{g}_j\|} \leq 0.1$

A 6 The user knows the crystal structure of the sample analysed at its unstrained state or can provide a reference in which is embedded the crystal structure information at its unstrained state.

A 7 The sample, from which the SMH is acquired, is mono-crystalline.

5.2.2 Theoretical Models

T 1 2D periodic sampling

- Equation: Equation (5)
- Description: In the 2D Cartesian coordinate system \mathcal{B} , the scanning grid can be seen as sampler S of a continuous function f . In the context of the STEM Moiré GPA project, the sampler is set to be periodic with the same periodicity p (called pixel size) in both x and y directions (2D Dirac comb). The resulting sampled version f_S of f can be represented as the following with δ representing the Dirac function:

$$\begin{aligned} \forall (x, y) \in \mathbb{R}^2, f_S(x, y) &= S(x, y) \times f(x, y) \\ \forall (x, y) \in \mathbb{R}^2, f_S(x, y) &= \sum_{n=-\infty}^{n=+\infty} \sum_{m=-\infty}^{m=+\infty} \delta(x - np, y - mp) \times f(x, y) \end{aligned} \quad (4)$$

For shorter notations, it is possible to define a set Q as follows $Q = \{\forall(n, m) \in \mathbb{Z}^2, \vec{q} = n\vec{u}_x + m\vec{u}_y\}$ and thus simplify eq. (4)

$$\forall (x, y) \in \mathbb{R}^2, f_S(\vec{r}) = \sum_{\vec{q} \in Q} \delta(\vec{r} - p\vec{q}) f(\vec{r}) \quad (5)$$

- Source: Trouver un truc pr sampling (bouquin sur la table d'isobel)
- Ref by: DD 2, IM 1, IM 4

T 2 Geometrical Phase Analysis

- Equation: Equation (9)
- Description: Let consider a function f decomposed in Fourier series as the following with

$$\begin{aligned} \forall \vec{r} = (x_1, \dots, x_n) \in \mathbb{R}^n, f(\vec{r}) &= \sum_{j=-\infty}^{j=+\infty} C_j e^{i(\vec{k}_j \cdot \vec{r})} \\ \forall \vec{r} = (x_1, \dots, x_n) \in \mathbb{R}^n, f(\vec{r}) &= \sum_{j=-\infty}^{j=+\infty} A_j e^{i((\vec{k}_j \cdot \vec{r}) + B_j)} \end{aligned} \quad (6)$$

If there is a small perturbation locally of the n-dimensions wave vector \vec{k}_j , it is possible to model it allowing B_j to be a function of \vec{r} .

$$\forall \vec{r} = (x_1, \dots, x_n) \in \mathbb{R}^n, f(\vec{r}) = \sum_{j=-\infty}^{j=+\infty} A_j e^{i((\vec{k}_j \cdot \vec{r}) + B_j(\vec{r}))} \quad (7)$$

The objective of GPA is to extract the perturbation, one chosen $B_j(\vec{r})$, from f in Fourier space. Let's consider the Fourier transform of f such that

$$\begin{aligned}
\forall \vec{\nu} = (\nu_1, \dots, \nu_n) \in \mathbb{R}^n, \forall \vec{r} = (x_1, \dots, x_n) \in \mathbb{R}^n, \tilde{f}(\vec{\nu}) &= \mathcal{FT}(f(\vec{r})) \\
\forall \vec{\nu} = (\nu_1, \dots, \nu_n) \in \mathbb{R}^n, \forall \vec{r} = (x_1, \dots, x_n) \in \mathbb{R}^n, \tilde{f}(\vec{\nu}) &= \sum_{j=-\infty}^{j=+\infty} \mathcal{FT}(C_j(\vec{r}) \times e^{i(\vec{k}_j \cdot \vec{r})}) \\
\forall \vec{\nu} \in \mathbb{R}^n, \tilde{f}(\vec{\nu}) &= \sum_{j=-\infty}^{j=+\infty} \widetilde{C}_j(\vec{\nu}) * \delta(\vec{\nu} - \vec{k}_j) \\
\forall \vec{\nu} \in \mathbb{R}^n, \tilde{f}(\vec{\nu}) &= \sum_{j=-\infty}^{j=+\infty} \widetilde{C}_j(\vec{\nu} - \vec{k}_j)
\end{aligned} \tag{8}$$

If all the \vec{k}_j are separated enough to be isolated with a mask, then $B_j(\vec{r})$ can be extracted by considering the inverse Fourier transform of the masked area and expressing the result in term of amplitude and phase. In mathematical formalism, $B_j(\vec{r})$ is extracted as follows with $\mathcal{G} = ([\nu_1^D, \nu_1^U], \dots, [\nu_n^D, \nu_n^U])$.

$$\begin{aligned}
\text{if } \exists M : \begin{cases} \mathbb{R}^n & \longrightarrow \mathbb{C} \\ \vec{\nu} & \longmapsto M(\vec{\nu}) \end{cases} / \begin{cases} M(\vec{\nu} - \vec{k}_j) \tilde{f}(\vec{\nu}) = \widetilde{C}_j(\vec{\nu} - \vec{k}_j) & \text{for } \vec{\nu} \in \mathcal{G} \\ M(\vec{\nu} - \vec{k}_j) \tilde{f}(\vec{\nu}) = 0 \end{cases} \\
\Rightarrow \begin{aligned} |\mathcal{FT}^{-1}[M(\vec{\nu}) \tilde{f}(\vec{\nu} + \vec{k}_j)]| &= |\mathcal{FT}^{-1}[\widetilde{C}(\vec{\nu})]| = A_j \\ \arg(\mathcal{FT}^{-1}[M(\vec{\nu}) \tilde{f}(\vec{\nu} + \vec{k}_j)]) &= \arg(\mathcal{FT}^{-1}[\widetilde{C}(\vec{\nu})]) = B_j(\vec{r}) \end{aligned}
\end{aligned} \tag{9}$$

- Source: [3,4]
- Ref by: DD 1, IM 2

Description of the GPA method in a 1D coordinate system

Let's consider a function f such that

$$\forall x \in \mathbb{R}, f(x) = C_0 e^{i(k_0 x)} + C_1 e^{i(k_1 x)}$$

Let's consider a small perturbation of k_1 modelled as the following

$$\forall x \in \mathbb{R}, f(x) = C_0 e^{i(k_0 x)} + A_1 e^{i(k_1 x) + iB_1(x)}$$

Applying the GPA method on f ,

$$\begin{aligned}
\forall \nu \in \mathbb{R}, \tilde{f}(\nu) &= C_0 \delta(\nu - k_0) + \widetilde{C}_1(\nu) * \delta(\nu - k_1) \\
\forall \nu \in \mathbb{R}, \tilde{f}(\nu) &= C_0 \delta(\nu - k_0) + \widetilde{C}_1(\nu - k_1)
\end{aligned}$$

Considering the perturbation around k_1 to be small and that k_0 and k_1 are enough separated such that the perturbation is located around k_1 in frequency space, it is possible to define a mask M such that:

$$\forall \nu \in \mathbb{R}, M(\nu) = \begin{cases} 1 & \text{for } \nu - k_1 \in [-\epsilon, +\epsilon] / k_0 \notin [k_1 - \epsilon, k_1 + \epsilon] \\ 0 & \end{cases}$$

In such case, multiply the mask M with the Fourier transform of f isolates \widetilde{C}_1 from the sum and can be independently transformed as follows:

$$\forall \nu \in \mathbb{R}, M(\nu - k_1) \widetilde{f}(\nu) = \widetilde{C}_1(\nu - k_1)$$

Setting, $\lambda = \nu - k_1$ and performing the inverse Fourier transform of the masked Fourier transform of f , the perturbation can be extracted.

$$\begin{aligned} \forall \nu \in \mathbb{R}, M(\lambda) \widetilde{f}(\lambda + k_1) &= \widetilde{C}_1(\lambda) \\ \forall x \in \mathbb{R}, \mathcal{FT}^{-1}[M(\lambda) \widetilde{f}(\lambda + k_1)] &= C_1(x) \\ \Rightarrow \begin{cases} |C_1(x)| = A_1 \\ \arg(C_1(x)) = B_1(x) \end{cases} \end{aligned}$$

T 3 Strain decomposition model

- Equation: Equation (10)
- Description: In infinitesimal strain theory with small displacement and small gradient of displacement (A 4, A 5), the displacement gradient tensor ∇u can be decomposed in two independent tensors: the symmetric strain tensor ε and the anti-symmetric rotation tensor ω . Their relationship can be described as follows:

$$\begin{aligned} \nabla u &= \varepsilon + \omega = \begin{bmatrix} \varepsilon_{xx} & \varepsilon_{xy} \\ \varepsilon_{xy} & \varepsilon_{yy} \end{bmatrix} + \begin{bmatrix} 0 & \omega_{xy} \\ -\omega_{xy} & 0 \end{bmatrix} \\ \varepsilon &= \frac{1}{2}(\nabla u + (\nabla u)^T) \\ \omega &= \frac{1}{2}(\nabla u - (\nabla u)^T) \end{aligned} \tag{10}$$

- Source: [3, 4]
- Ref by: DD 3, IM 3, IM 5

5.2.3 General Definitions

Non applicable for STEM Moiré GPA software.

5.2.4 Data Definitions

DD 1 Variation of the crystalline wave vector $\Delta\vec{g}_j$ (strain in crystal lattice)

- ★ Equation: Equation (13)
- ★ Description: For the purpose of the STEM Moiré GPA, only mono-crystalline samples are analysed (A 7). In the case of a perfect periodic atomic arrangement, the crystalline lattice I_c can be described in Fourier series with C_j the complex Fourier coefficient related to the crystalline wave vector \vec{g}_j in the 2D Cartesian system.

$$\forall (x, y) \in \mathbb{R}^2, I_C(\vec{r}) = \sum_{j=-\infty}^{j=+\infty} C_j e^{i(\vec{g}_j \cdot \vec{r})} \quad (11)$$

If the crystal is elastically deformed, the relative position of the atoms will be slightly modified from their original unstrained configuration. The local deformation is breaking locally the perfect periodicity of the crystalline lattice. In the case of small deformation (A 5), C_j can be allowed to vary in space in eq. (11). Representing C_j with a phase A_j and an amplitude P_j , a pure displacement is only contributing in the phase component. The strain information is therefore embedded in $P_{g_j}(\vec{r})$ such that $P_{g_j}(\vec{r}) = 2\pi\Delta\vec{g}_j(\vec{r}) \cdot \vec{r}$ where $\Delta\vec{g}_j$ represent the variation of the crystalline vector compared to its unstrained state.

$$\begin{aligned} \forall (x, y) \in \mathbb{R}^2, I_C(\vec{r}) &= \sum_{j=-\infty}^{j=+\infty} C_j(\vec{r}) e^{i(\vec{g}_j \cdot \vec{r})} \\ \forall (x, y) \in \mathbb{R}^2, I_C(\vec{r}) &= \sum_{j=-\infty}^{j=+\infty} A_j e^{i(\vec{g}_j \cdot \vec{r}) + iP_{g_j}(\vec{r})} \end{aligned} \quad (12)$$

By applying GPA (T 2) on eq. (12), $P_{g_j}(\vec{r})$ can be extracted. Then by applying A 4, the gradient ∇ of $P_{g_j}(\vec{r})$ can be approximate as follows

$$\nabla P_{g_j}(\vec{r}) = 2\pi[\nabla(\Delta\vec{g}_j \cdot \vec{r})] \approx 2\pi\overrightarrow{\Delta g_j(r)} \quad (13)$$

- ★ Source: [3]
- ★ Ref by: T 2, IM 3, IM 5

DD 2 STEM Moiré hologram I_{SMH}

- ★ Equation: Equation (18)

★ Description: Combining eq. (12) and eq. (4), a STEM Moiré hologram I_{SMH} can be described as follows

$$\forall (x, y) \in \mathbb{R}^2, I_{SMH}(\vec{r}) = \sum_{q \in Q} \delta(\vec{r} - p\vec{q}) \times \sum_{j=-\infty}^{j=+\infty} A_j e^{i(\vec{g}_j \cdot \vec{r}) + iP_{g_j}(\vec{r})} \quad (14)$$

By modifying p the scanning periodicity (or the pixel size), it is possible to adjust the spatial frequency of the SMH solving eq. (14). Applying A 1 and A 3, the expression of I_C in eq. (12) is simplified since the series becomes a finite sum.

$$\forall (x, y) \in \mathbb{R}^2, I_C(\vec{r}) = \sum_{j=-j_{lim}}^{j=+j_{lim}} A_j e^{i(\vec{g}_j \cdot \vec{r}) + iP_{g_j}(\vec{r})} \quad (15)$$

Therefore, the STEM Moiré hologram I_{SMH} is also simplified as follows:

$$\forall (x, y) \in \mathbb{R}^2, I_{SMH}(\vec{r}) = \sum_{q \in Q} \delta(\vec{r} - p\vec{q}) \times \sum_{j=-j_{lim}}^{j=+j_{lim}} A_j e^{i(\vec{g}_j \cdot \vec{r}) + iP_{g_j}(\vec{r})} \quad (16)$$

Taking the Fourier transform of I_{SMH} , it is possible to notice that \tilde{I}_{SMH} is $(1/p, 1/p)$ periodic.

$$\begin{aligned} \forall (\nu_x, \nu_y) \in \mathbb{R}^2, \tilde{I}_{SMH}(\nu_x, \nu_y) &= \frac{1}{p^2} \sum_{n=-\infty}^{n=+\infty} \sum_{m=-\infty}^{m=+\infty} \delta(\nu_x - \frac{n}{p}, \nu_y - \frac{m}{p}) * \tilde{I}_C(\nu_x, \nu_y) \\ \forall (\nu_x, \nu_y) \in \mathbb{R}^2, \tilde{I}_{SMH}(\nu_x, \nu_y) &= \frac{1}{p^2} \sum_{n=-\infty}^{n=+\infty} \sum_{m=-\infty}^{m=+\infty} \tilde{I}_C(\nu_x - \frac{n}{p}, \nu_y - \frac{m}{p}) \\ \forall (\nu_x, \nu_y) \in \mathbb{R}^2, \tilde{I}_{SMH}(\nu_x + \frac{1}{p}, \nu_y + \frac{1}{p}) &= \tilde{I}_{SMH}(\nu_x, \nu_y) \end{aligned} \quad (17)$$

Therefore it is possible to restrain the calculation of \tilde{I}_{SMH} for $\vec{\nu} \in [-\frac{1}{2p}, \frac{1}{2p}]^2 = \Gamma$ and respect assumption A 2. Nevertheless, eq. (16) has still an infinite set of terms in the sum since the set Q is not finite. Therefore, eq. (16), at this stage, is not unusable. Applying A 1, $\forall (\nu_x, \nu_y) \notin [-g_{lim}, g_{lim}]^2, \tilde{I}_C(\nu_x, \nu_y) = 0$. As a consequence, $\exists (N_{lim}, N_{lim}) \in \mathbb{N}^2 / \forall (\nu_x, \nu_y) \in \Gamma, \tilde{I}_C(\nu_x - \frac{N_{lim}}{p}, \nu_y - \frac{N_{lim}}{p}) = 0$. It is possible thus to define $Q_{lim} = \{\forall (n, m) \in \mathbb{Z}^2 \cap [-N_{lim}, N_{lim}], \vec{q} = n\vec{u}_x + m\vec{u}_y\}$ and rewrite eq. (17) as the following:

$$\begin{aligned} \forall (\nu_x, \nu_y) \in \Gamma, \tilde{I}_{SMH}(\nu_x, \nu_y) &= \frac{1}{p^2} \sum_{n=-N_{lim}}^{n=+N_{lim}} \sum_{m=-N_{lim}}^{m=+N_{lim}} \tilde{I}_C(\nu_x - \frac{n}{p}, \nu_y - \frac{m}{p}) \\ \forall \vec{\nu} \in \Gamma, \tilde{I}_{SMH}(\vec{\nu}) &= \frac{1}{p^2} \sum_{\vec{q} \in Q_{lim}} \tilde{I}_C(\vec{\nu} - \frac{\vec{q}}{p}) \end{aligned} \quad (18)$$

★ Source: [5]

★ Ref by: DD 1, T 1, IM 1, IM 4

From sampling to interferometry

Since the Dirac comb function is also periodic, the sampler can also be represented into Fourier series

$$\forall(x, y) \in \mathbb{R}^2, S(\vec{r}) = \sum_{q \in Q} \delta(\vec{r} - p\vec{q}) = \frac{1}{p^2} \sum_{q \in Q} e^{\frac{i}{p} \vec{q} \cdot \vec{r}} \quad (19)$$

Using eq. (19) in eq. (16), it is possible to recognize an interference equation between multiple plane waves (a more complex version of eq. (3)).

$$\begin{aligned} \forall(x, y) \in \mathbb{R}^2, I_{SMH}(\vec{r}) &= \frac{1}{p^2} \sum_{q \in Q} \sum_{j=-j_{lim}}^{j=+j_{lim}} A_j e^{i(\vec{g}_j \cdot \vec{r} + \frac{i}{p} \vec{q} \cdot \vec{r} + i P_{g_j}(\vec{r}))} \\ \forall(x, y) \in \mathbb{R}^2, I_{SMH}(\vec{r}) &= \frac{1}{p^2} \sum_{q \in Q} \sum_{j=-j_{lim}}^{j=+j_{lim}} A_j e^{i((\vec{g}_j - \frac{i}{p} \vec{q}) \cdot \vec{r} + i P_{g_j}(\vec{r}))} \end{aligned} \quad (20)$$

DD 3 Deformation gradient tensor ∇u from crystalline wave vectors

Equation: Equation (21)

Description: Let's consider $\vec{g}_j = \vec{g}_{j_{uns}} + \Delta \vec{g}_j$ with $\vec{g}_{j_{uns}}$ representing the crystalline wave vector at its unstrained state. If $\vec{g}_{j_{uns}} = g_{j_{x_{uns}}} \vec{u}_x + g_{j_{y_{uns}}} \vec{u}_y$ and $\Delta \vec{g}_j = \Delta g_{j_x} \vec{u}_x + \Delta g_{j_y} \vec{u}_y$ are known in the base \mathcal{B} for two non-collinear crystalline wave vectors (only valid for mono-crystalline samples A 7), then the strain deformation tensor can be deduced by calculating first both the unstrained matrix G and the variation of the crystalline wave vectors matrix ΔG . Then, under assumptions A 4 and A 5, the deformation gradient tensor ∇u is estimated as the following with I_d representing the identity matrix (see annexe D in [3] and equation (30) in [4]).

$$\begin{aligned} G_{uns} &= \begin{bmatrix} g_{1_{x_{uns}}} & g_{1_{y_{uns}}} \\ g_{2_{x_{uns}}} & g_{2_{y_{uns}}} \end{bmatrix} \\ \Delta G &= \begin{bmatrix} \Delta g_{1_x} & \Delta g_{1_y} \\ \Delta g_{2_x} & \Delta g_{2_y} \end{bmatrix} \\ \nabla u &= (\Delta G^T)^{-1} G_{uns}^T - I_d \end{aligned} \quad (21)$$

Source: [3, 4]

Ref by: T 3, DD 1, IM 3, IM 5

5.2.5 Instance Models

IM 1 Simulate the SMH on a reference to determine \vec{q}_j for each \vec{g}_j^M

- **Input**: $I_{C_{ref}}, p$
- **Output**: $\tilde{I}_{SMH_{sim}}, \overrightarrow{q_{n_j, m_j}}, \vec{g}_j^{M_{ref}}$

- **Description:** Considering that $I_{C_{ref}}$ represents a 2D array of the sample monocrystalline lattice (A 6, A 7), the STEM Moiré hologram with a scanning grid periodicity of p and respecting the assumptions, A 1, A 2, A 3, is simulated to compare it to the experimental STEM Moiré hologram $I_{SMH_{exp}}$ in Fourier space. Using DD 2, the Fourier transform of the simulated STEM Moiré $\tilde{I}_{SMH_{sim}}$ hologram is calculated using eq. (18):

$$\forall \vec{\nu} \in \Gamma, \tilde{I}_{SMH_{sim}}(\vec{\nu}) = \frac{1}{p^2} \sum_{\vec{q} \in Q_{lim}} \tilde{I}_{C_{ref}}(\vec{\nu} - \frac{\vec{q}}{p}) \quad (22)$$

N_{lim} in Q_{lim} is set with respect to the highest spatial frequency resolved in $I_{C_{ref}}$ such that $\forall j \in [-j_{lim}, j_{lim}], \mathcal{C}(\max(||\vec{g}_j^{C_{ref}}||) \times p) = N_{lim}$ where \mathcal{C} is the ceiling function.

- **Source:** [5]
- **Ref by:** IM 4, IM 5, DD 2

Details on the extraction of $\overrightarrow{q_{n_j, m_j}}$ and $\overrightarrow{g_j^{M_{ref}}}$

For the moment, the extraction the $\overrightarrow{q_{n_j, m_j}}$ for a specific $\overrightarrow{g_j^{M_{ref}}}$ is manual and should be done by the user. IM 1 is transforming the $\overrightarrow{g_j^{C_{ref}}}$ into $\overrightarrow{g_j^{M_{ref}}}$ as the following:

$$\overrightarrow{g_j^{C_{ref}}} - \overrightarrow{q_{n_j, m_j}} \times p = \overrightarrow{g_j^{M_{ref}}} \quad (23)$$

This simple equation comes from eq. (20) by restraining SMH_{sim} in Γ . Identifying the frequency component, the following condition has to be respected:

$$(\overrightarrow{g_j^{C_{ref}}} - \overrightarrow{q} \times p) \in \Gamma$$

Since $\Gamma = [-\frac{1}{2p}, \frac{1}{2p}]^2$, there is only one possible $\overrightarrow{q} \times p$ vector that transform $\overrightarrow{g_j^{C_{ref}}}$ in Γ . Naming the only option $\overrightarrow{q_{n_j, m_j}}$ and the result of the transformation $\overrightarrow{g_j^{M_{ref}}}$ as the Moiré wave vector, equation eq. (23) can be deduced.

IM 2 GPA on a selected Moiré wave vector from $I_{SMH_{exp}}$

- **Input:** $I_{SMH_{exp}}, M_j$
- **Output:** $P_{\Delta \overrightarrow{g_j^{M_{exp}}}}, \overrightarrow{g_j^{M_{exp}}}, \Delta \overrightarrow{g_j^{M_{exp}}}$
- **Description:** Applying T 2, DD 1 and using assumption A 1, $I_{SMH_{exp}}$ can be interpreted as follows

$$\forall \vec{r} \in \mathbb{I}, I_{SMH_{exp}} = \sum_{j=-j_{lim}}^{j=+j_{lim}} A_j e^{i(\overrightarrow{g_j^{M_{exp}}} \cdot \vec{r} + P_{\Delta \overrightarrow{g_j^{M_{exp}}}})} \quad (24)$$

Applying GPA under the assumptions A 4 and A 5, $P_{\Delta\vec{g}_j^{Mexp}}$ is extracted using a mask M_j centred around $(g_{j_x}^{Mexp}, g_{j_y}^{Mexp})$ such that

$$\forall \nu \in \Gamma, M_j(\nu) = \begin{cases} 1 & \text{for } \|\vec{\nu} - \vec{g}_j^{Mexp}\| \leq \epsilon / \forall l \neq j, \|\vec{\nu} - \vec{g}_l^{Mexp}\| \geq \epsilon \\ 0 & \end{cases} \quad (25)$$

Finally considering $M_j \tilde{I}_{SMHexp}$ the masked Fourier transform of I_{SMHexp} ,

$$\forall \vec{r} \in \mathbb{I}, P_{\Delta\vec{g}_j^{Mexp}}(\vec{r}) = \arg(\mathcal{FT}^{-1}[M_j \tilde{I}_{SMHexp}])(\vec{r}) \quad (26)$$

Finally the gradient of the $P_{\Delta\vec{g}_j^{Mexp}}(\vec{r})$ is calculated to extract $\Delta\vec{g}_j^{Mexp}(\vec{r})$.

$$\forall \vec{r} \in \mathbb{I}, \nabla P_{\Delta\vec{g}_j^{Mexp}}(\vec{r}) = 2\pi \Delta\vec{g}_j^{Mexp}(\vec{r}) \quad (27)$$

- **Source:** [3]
- **Ref by:** IM 3, IM 5, DD 1, T 2, DD 2

IM 3 Determine an unstrained area in the geometric phase image

- **Input:** $\Delta\vec{g}_j^{Mexp}, U, p$
- **Output:** \vec{g}_{juns}^{Mexp}
- **Description:** From DD 1 and IM 2, $\forall \vec{r} \in \mathbb{I}, \nabla P_{\Delta\vec{g}_j^{Mexp}}(\vec{r}) = 2\pi \Delta\vec{g}_j^{Mexp}(\vec{r})$. An area $U \in \mathbb{I}$ of $\Delta\vec{g}_j^{Mexp}$ is set by the user as an unstrained reference, so $\Delta\vec{g}_j^{Mexp}$ is set to $\vec{0}$ in U . The operation can be formalized as follows with $card(U)$ representing the cardinality of the set U .

$$\forall \vec{r} \in U, \vec{g}_j^{Mexp} = \frac{1}{card(U) \times p^2} \sum_{\vec{r} \in U} \vec{g}_{juns}^{Mexp}(\vec{r}) \quad (28)$$

- **Source:** [3]
- **Ref by:** IM 2, DD 1, DD 3

IM 4 Convert the Moiré wave vector into the Crystalline wave vector

- **Input:** $\vec{g}_{juns}^{Mexp}, \Delta\vec{g}_j^{Mexp}, \overrightarrow{q_{n_j, m_j}}, p$
- **Output:** $\Delta\vec{g}_j^{Cexp}, \vec{g}_{juns}^{Cexp}$
- **Description:** The conversion is a basic affine vectorial transformation and is highlighted in eq. (29)

$$\begin{cases} \vec{g}_{juns}^{Cexp} = \vec{g}_{juns}^{Mexp} + p \times \overrightarrow{q_{n_j, m_j}} \\ \Delta\vec{g}_j^{Cexp} = \Delta\vec{g}_j^{Mexp} + p \times \overrightarrow{q_{n_j, m_j}} \end{cases} \quad (29)$$

- Source: [5]
- Ref by: IM 1, IM 2, IM 3, DD 2, DD 3, DD 1

IM 5 Strain calculation using 2 non-crystalline wave vectors

- Input: $g_{1_{uns_x}}^{Cexp}, g_{1_{uns_y}}^{Cexp}, g_{2_{uns_x}}^{Cexp}, g_{2_{uns_y}}^{Cexp}, \Delta g_{1_x}^{Cexp}, \Delta g_{1_y}^{Cexp}, \Delta g_{2_x}^{Cexp}, \Delta g_{2_y}^{Cexp}$
- Output: $\varepsilon_{xx}, \varepsilon_{xy}, \varepsilon_{yy}, \omega_{xy}, I_{\varepsilon_{xx}}, I_{\varepsilon_{xy}}, I_{\varepsilon_{yy}}, I_{\omega_{xy}}$
- Description: Applying DD 3 and T 3, the matrices G_{uns} and ΔG are formed to calculate the deformation gradient tensor ∇u and then the rotation ω and strain ε tensors on each pixel. The data is then displayed in form of 2D arrays.
- Source: [3, 4]
- Ref by: IM 4, DD 3, T 3

5.2.6 Data Constraints

DC 1 U should be the same in both $\Delta \vec{g}_j^{Mexp}$ with $j = \{1, 2\}$ in IM 3.

DC 2 The pixel size p should be strictly positive ($p > 0$).

DC 3 Both I_{Cref} and I_{SMHexp} can be dm3 files.

5.2.7 Properties of a Correct Solution

The correctness of the solution must be judged by the user him/herself based on the knowledge of the sample analysed.

6 Requirements

This section provides the functional requirements, the tasks that the software is expected to complete, and the nonfunctional requirements, the qualities that the software is expected to exhibit.

6.1 Functional Requirements

- R 1 Provide an environment for the user to input I_{SMHexp} and I_{Cref} .
- R 2 Verify the format of the inputs I_{SMHexp} and I_{Cref} .
- R 3 Output $\tilde{I}_{SMHexp}, \tilde{I}_{SMHsim}$.

- R 4** Display to the user $\tilde{I}_{SMH_{exp}}$ and $\tilde{I}_{SMH_{sim}}$ to allow the user to determine $\overrightarrow{q_{n_j, m_j}}$ for each $\overrightarrow{g_j^{M_{ref}}}$.
- R 5** Provide an environment for the user to input M_j for each $\overrightarrow{g_j^{M_{exp}}}$ with $j = \{1, 2\}$ on $\tilde{I}_{SMH_{exp}}$.
- R 6** Verify both M_j inputs with $j = \{1, 2\}$.
- R 7** Output both $P_{\Delta \overrightarrow{g_j^{M_{exp}}}}$ and $\overrightarrow{g_j^{M_{exp}}}$ with $j = \{1, 2\}$.
- R 8** Display both $\Delta \overrightarrow{g_j^{M_{exp}}}$ with $j = \{1, 2\}$ and provide an environment for the user to input U .
- R 9** Verify the input U .
- R 10** Output both $\overrightarrow{g_{j_{uns}}^{M_{exp}}}$ with $j = \{1, 2\}$.
- R 11** Provide an environment to the user to input both $\overrightarrow{q_{n_j, m_j}}$ with $j = \{1, 2\}$.
- R 12** Output both $\Delta \overrightarrow{g_j^{C_{exp}}}$ and both $\overrightarrow{g_{j_{uns}}^{C_{exp}}}$ with $j = \{1, 2\}$.
- R 13** Output $\varepsilon_{xx}, \varepsilon_{xy}, \varepsilon_{yy}, \omega_{xy}$ on each element of the array to form $I_{\varepsilon_{xx}}, I_{\varepsilon_{xy}}, I_{\varepsilon_{yy}}, I_{\omega_{xy}}$.
- R 14** Display to the user $I_{\varepsilon_{xx}}, I_{\varepsilon_{xy}}, I_{\varepsilon_{yy}}, I_{\omega_{xy}}$.

6.2 Nonfunctional Requirements

- NR 1** The software shall be reproducible on the most used operating systems (Linux, Mac, Windows).
- NR 2** The software shall run on a classic PC desktop.
- NR 3** The data display shall be readable by the user (standard font, standard font size, standard organisation of display, standard colors).
- NR 4** All the environments expecting an input from the user shall be accessible and executable quickly (in a few seconds time frame).
- NR 5** The user shall be able to extract the final data in text or csv format.
- NR 6** The STEM Moiré GPA software shall be able to save the information processed in a temporary file (or cache file) to prevent a loss of information when the software or the PC crashes.
- NR 7** When starting the STEM Moiré GPA software, the existence of a temporary file should be checked and the user should be asked if he or she wants to start the software from the previously saved temporary file.
- NR 8** The precision on the final results from STEM Moiré GPA software should be limited only by the quality of the initial SMH_{exp} and by the user inputs.
- NR 9** The inaccuracy of the STEM Moiré GPA software should not be greater than the precision detailed in NR 8.

7 Likely Changes (or Possible Changes)

LC 1 The determination of $\overrightarrow{q_{n_j, m_j}}$ for a specific $\overrightarrow{g_j^{Mref}}$ in IM 1 could be done automatically by the software. Nevertheless, the notion of "spatial frequency overlap" needs to be introduced and will complexify STEM Moiré GPA software. A decision has to be made between keeping a more simple version of STEM Moiré GPA software while accepting more inputs from the user and, a more simple user experience of STEM Moiré GPA software with a more demanding implementation phase.

LC 2 In T 2, the argument component in eq. (9) has a constraint to output values between $[0; 2\pi[$ only. If the phase varies more than in this interval phase unwrapping method needs to be implemented to process the data correctly. While initially considered as a lower level of implementation, different phase unwrapping algorithm exists with different performance. Since accuracy and precision have been identified as a non-functional requirement, the unwrapping model should be considered in the SRS document. Nevertheless, a deeper understanding of the different algorithms is first required before documenting them.

8 Traceability Matrices and Graphs

The traceability matrices section relates the interactions between different elements of the STEM Moiré GPA software. If a cell of the table is crossed, it means that if the element from the column is modified, the section in the horizontal line has to be changed. The traceability matrices are described below:

- Table 2 is showing the dependencies between the theoretical models, the data definitions and the instance models. Since STEM Moiré GPA software is mostly sequential, most dependencies are related to the input/output sequences. However, DD 1 reveals to be a very dependant element and will require an important work if modified. Since the definition of strain in the crystalline lattice is defined in this specific parameter, a strong relation with any section of STEM Moiré GPA software can be indeed expected.
- Table 3 is highlighting the dependencies of the theoretical models, the data definitions and the instance models with respect to the assumptions. Two families affecting their respective sections can be observed:
 - Assumptions related to the sample A 4, A 5, A 6, A 7.
 - Assumptions related to the microscope A 1, A 2, A 3.

The assumptions were used to cover a certain variety of sample and to not be sensitive to different microscopes. However for dedicated applications, some of this assumptions can be removed.

- Table 4 is showing the dependencies between the instance models and the requirements. The sequential structure of STEM Moiré GPA is again visible here. IM 1 and

IM 2 are the key elements of the software in which heavy calculations and multiple interactions with the users are performed. The high number of related requirements can be explained by the complexity factor.

| | T 1 | T 2 | T 3 | DD 1 | DD 2 | DD 3 | IM 1 | IM 2 | IM 3 | IM 4 | IM 5 |
|------|-----|-----|-----|------|------|------|------|------|------|------|------|
| T 1 | | | | | | | | | | | |
| T 2 | | | | | | | | | | | |
| T 3 | | | | | | | | | | | |
| DD 1 | | X | | | | | | | | | |
| DD 2 | X | | | X | | | | | | | |
| DD 3 | | | | X | | | | | | | |
| IM 1 | X | | | X | X | | | | | | |
| IM 2 | | X | | X | X | | X | | | | |
| IM 3 | | | X | X | | X | | X | | | |
| IM 4 | X | | | X | X | | X | | X | | |
| IM 5 | | | X | X | | X | | | | X | |

Table 2: Traceability Matrix for the theoertical models TM, the data definitions DD and the instance models IM

| | A 1 | A 2 | A 3 | A 4 | A 5 | A 6 | A 7 |
|------|-----|-----|-----|-----|-----|-----|-----|
| T 1 | | | | | | | |
| T 2 | | | | | | | |
| T 3 | | | | X | X | | |
| DD 1 | | | | X | X | | X |
| DD 2 | X | X | X | | | | |
| DD 3 | | | | X | X | | X |
| IM 1 | X | X | X | | | X | X |
| IM 2 | X | | | X | X | | |
| IM 3 | | | | | | | |
| IM 4 | | | | | | | |
| IM 5 | | | | X | X | | |

Table 3: Traceability Matrix linking the assumptions to the theoertical models TM, the data definitions DD and the instance models IM

| | IM 1 | IM 2 | IM 3 | IM 4 | IM 5 | R 1 | R 2 | R 3 | R 4 | R 5 | R 6 | R 7 | R 8 | R 9 | R 10 | R 11 | R 12 | R 13 | R 14 |
|------|------|------|------|------|------|-----|-----|-----|-----|-----|-----|-----|-----|-----|------|------|------|------|------|
| IM 1 | | | | | | X | | | | | | | | | | | | | |
| IM 2 | X | | | | | | | X | X | X | | X | X | | | | | | |
| IM 3 | | X | | | | | | | | | | X | X | | X | | | | |
| IM 4 | X | | X | | | X | | | X | | | | X | | X | X | X | | |
| IM 5 | | | | X | | | | | | | | | | | | | X | X | X |
| R 1 | X | X | | | | | | | | | | | | | | | | | |
| R 2 | X | X | | | | X | | | | | | | | | | | | | |
| R 3 | X | X | | | | X | | | | | | | | | | | | | |
| R 4 | X | X | | | | X | | X | | | | | | | | | | | |
| R 5 | | X | | | | | | X | X | | | | | | | | | | |
| R 6 | | X | | | | | | | | X | | | | | | | | | |
| R 7 | | X | | | | | | | | X | | | | | | | | | |
| R 8 | | X | X | | | | | | X | | | X | | | | | | | |
| R 9 | | | | X | | | | | | | | | X | | | | | | |
| R 10 | | | | X | | | | | | | | | X | | | | | | |
| R 11 | X | | | X | | | | | | | | | | | | | | | |
| R 12 | | | | X | | | | | | | | | | | | X | | | |
| R 13 | | | | | X | | | | | | | | | | | | X | | |
| R 14 | | | | | X | | | | | | | | | | | | | X | |

Table 4: Traceability Matrix for the instance models IM and the requirements R

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9 Appendix

9.1 Symbolic Parameters